Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/779,779	NIIYA, HIROTAKA	
Examiner	Art Unit	

Wen-Ying P. Chen

2871

	SEAR	CHED	
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH N (INCLUDING SEAR))
	DATE	EXMR
Key word search on EAST	5/9/2005	wpc
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